


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/768,234	HUNLETH ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Le Nguyen	2174	

SEARCHED			
Class	Subclass	Date	Examiner
715	838	2/25/2007	LVN

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
US-PGPub, USPAT: 715/838		2/25/2007	LVN

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
inventor name search	2/25/2007	LVN
US-PGPub, USPAT: 715/838,708,711,767,802,822,823, 859,860,719-732,716,739; 725/37-61	2/25/2007	LVN